



Atomic force microscopes

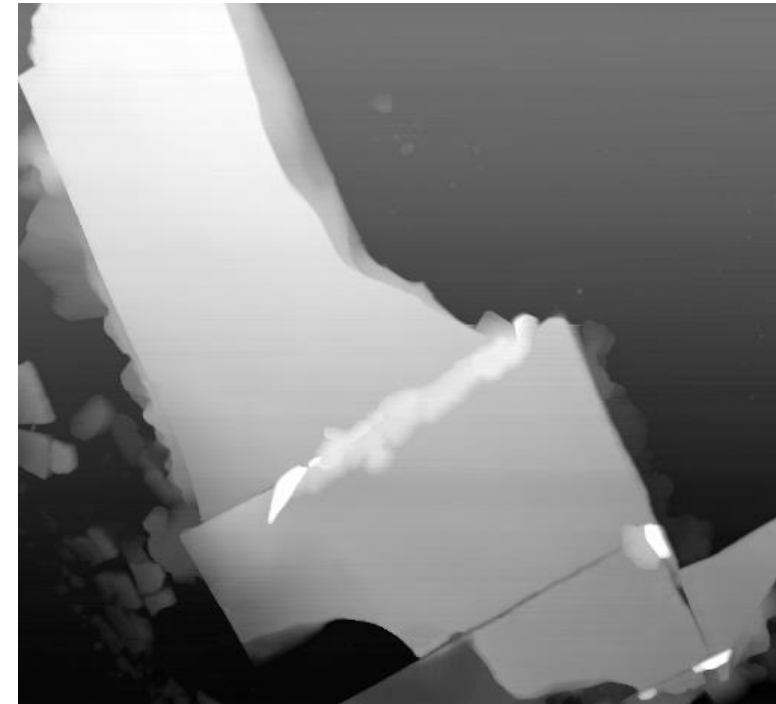
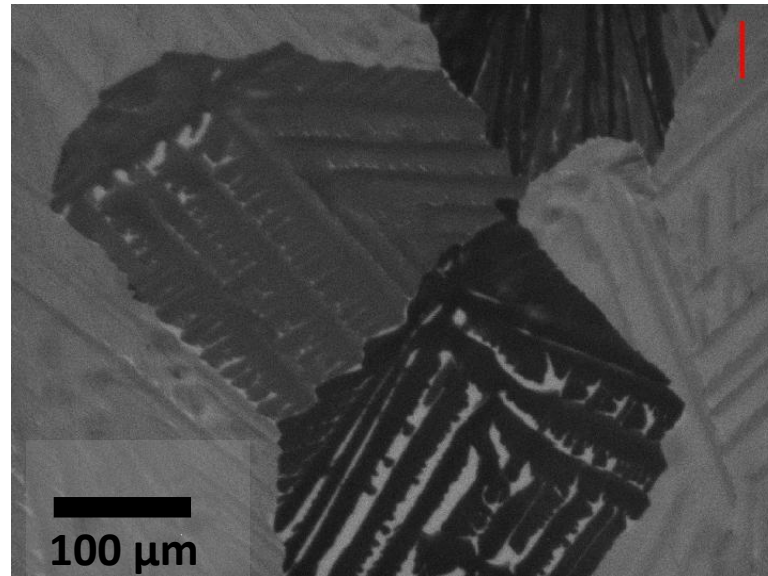
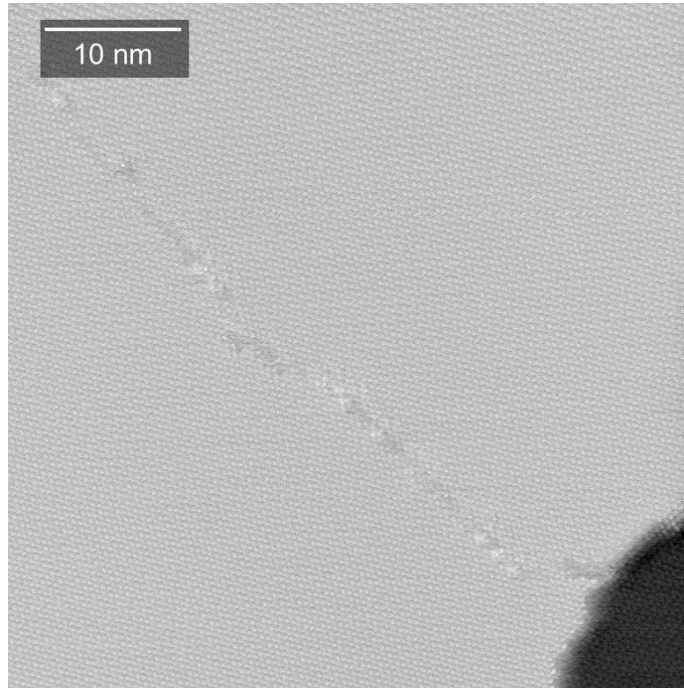
Gabriel Schulmann



Our work



- Our lab looks at the structural optical and electronic properties of materials on the nanometer scale
- We do this with scanning probe microscopy, our lab has an atomic force microscope and a scanning tunneling microscope



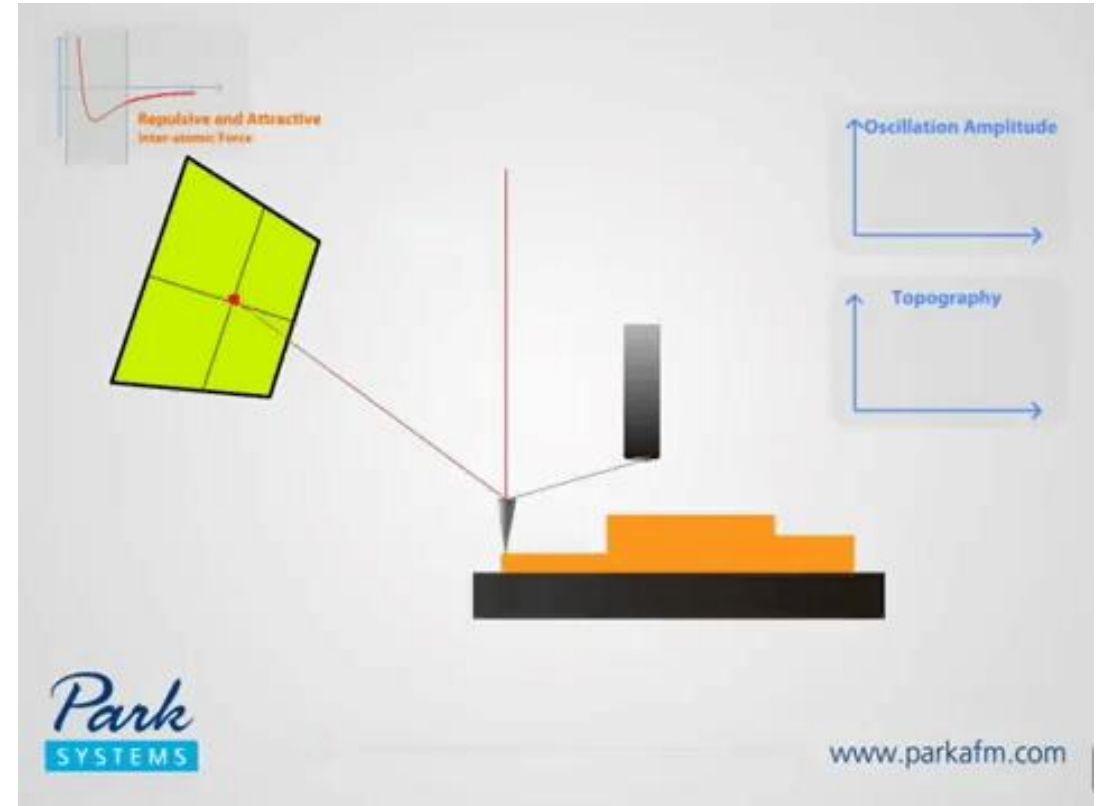


What is an atomic force microscope?

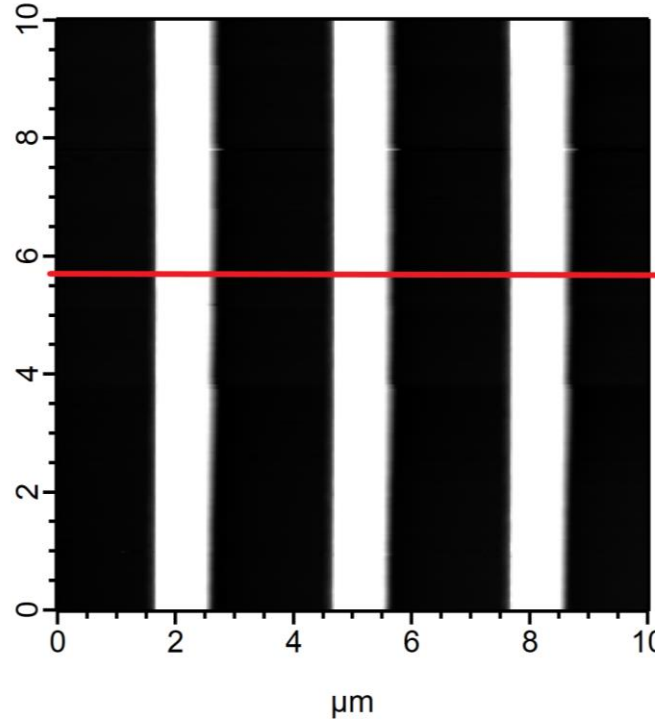
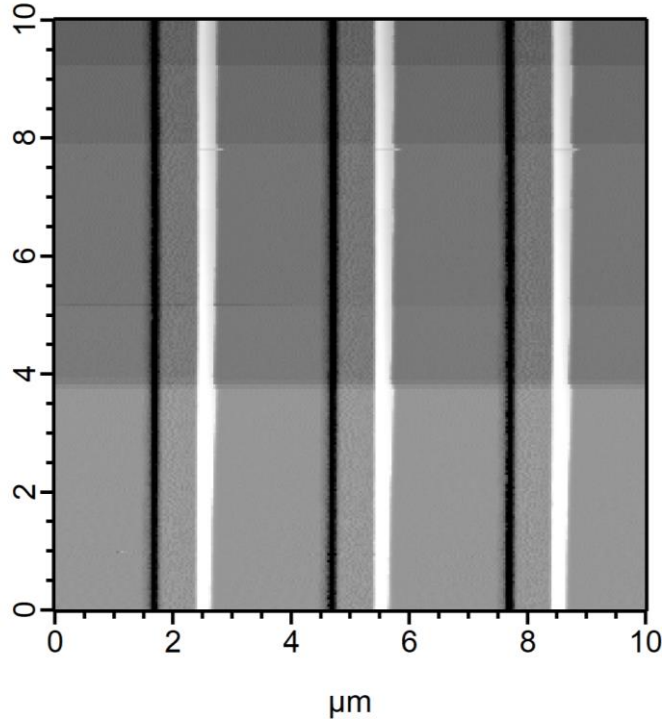
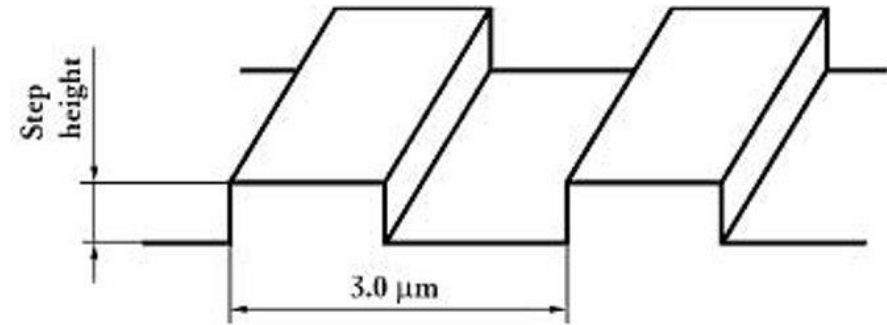
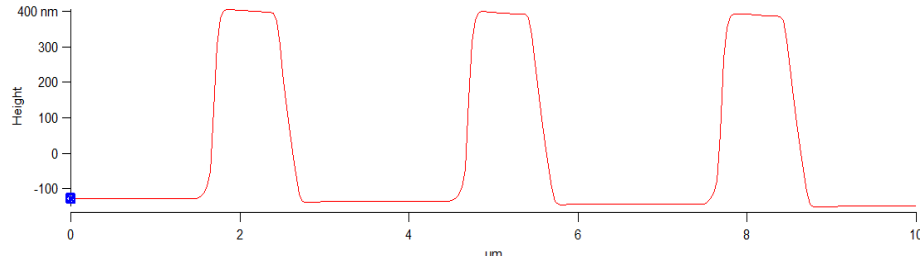


- An atomic force microscope (AFM) is a scanning probe microscope with nanometer resolution.
- The AFM can provide topographical data and electronic mapping across a designated scan window.
- I spent the summer learning how to take topographical images with the AFM.

- When the tip is close to the surface there will be a interaction force between the tip and the sample
- The cantilever tip will scan across a line oscillating at a set frequency and amplitude
- The AFM will adjust the distance between the tip and the sample to keep the oscillation amplitude constant
- The height corrections and the amplitude data from the line scans are stitched together to form an image



Test Grating Images



- The height of the features is 540 nm, and their period is 3.02 μm
- Test gratings are useful for determining the condition of the cantilever tip



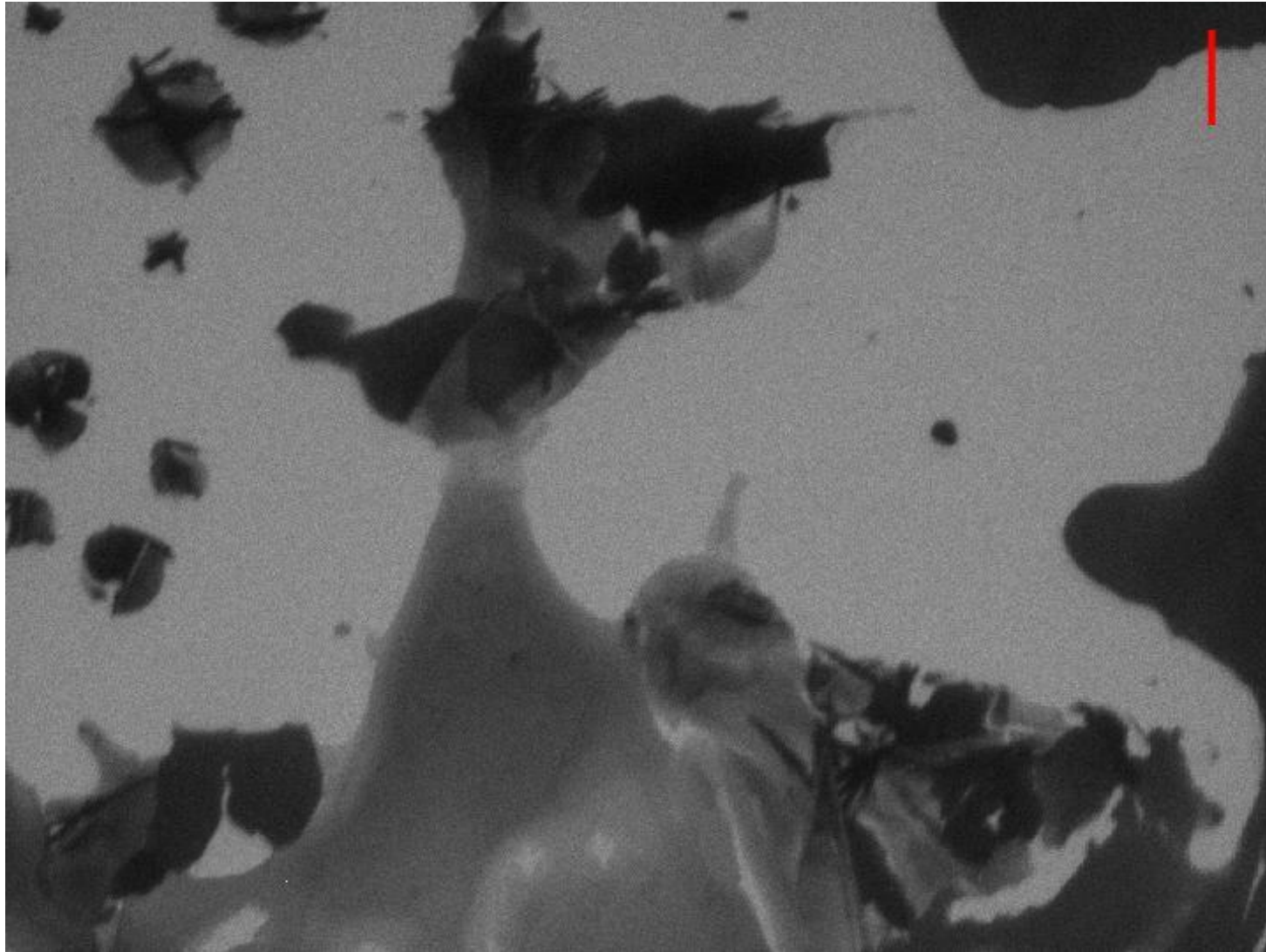
Phthalocyanine (H₂-OBPc) thin film project



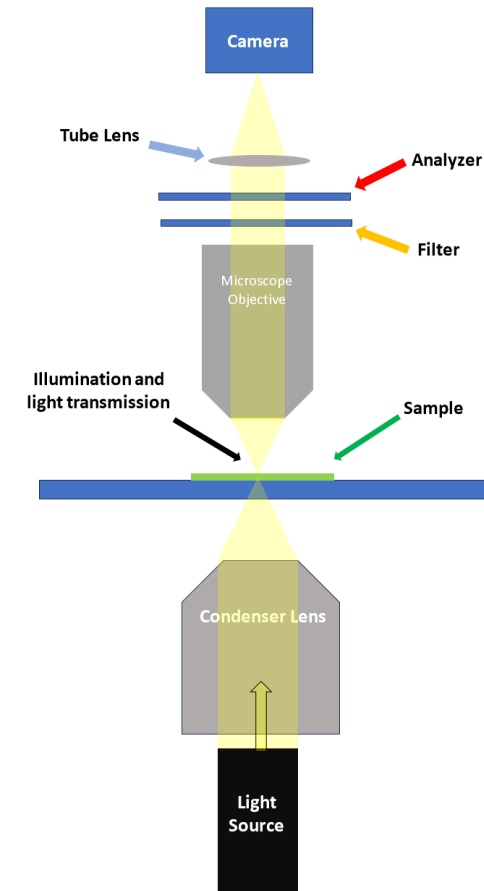
- My focus this summer has been imaging phthalocyanine samples from the Furis group.
- Phthalocyanine is an organic semiconductor with potential applications in electronic devices.
- These thin film samples are printed onto a functionalized ITO in the Furis lab and then they go through our image process
- The first step is to survey the sample for interesting regions with an optical microscope



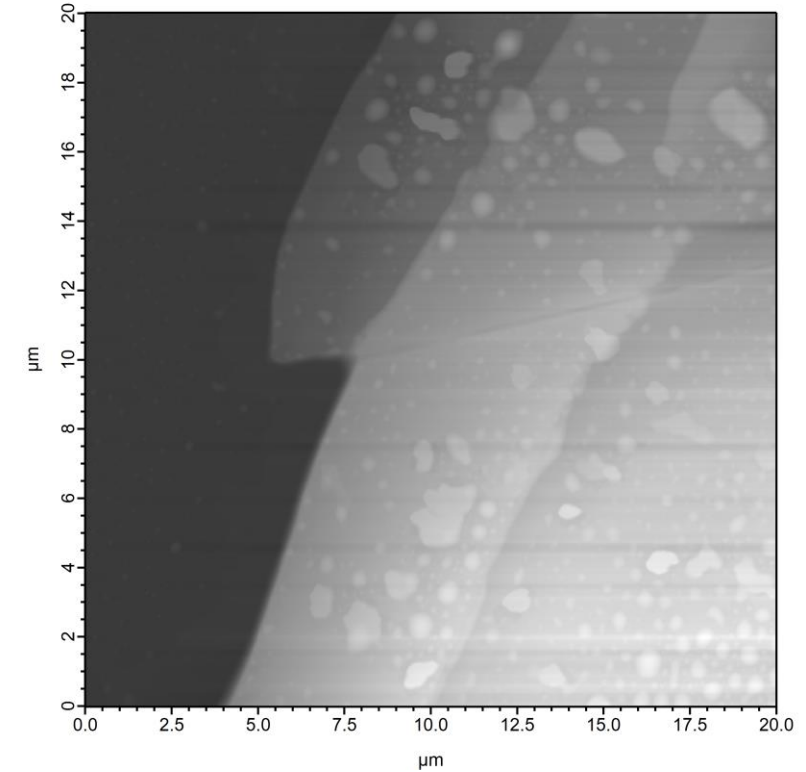
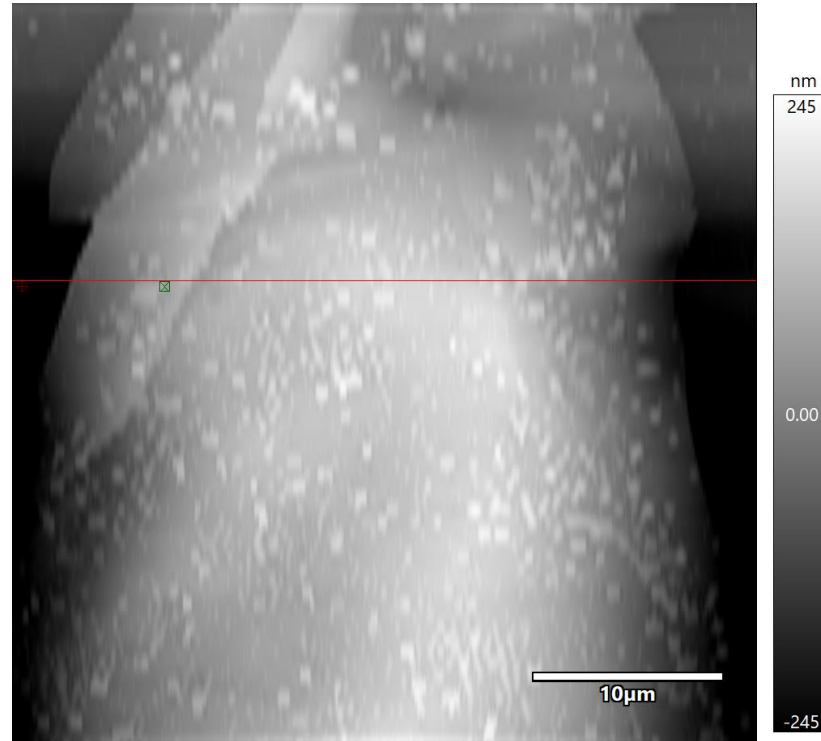
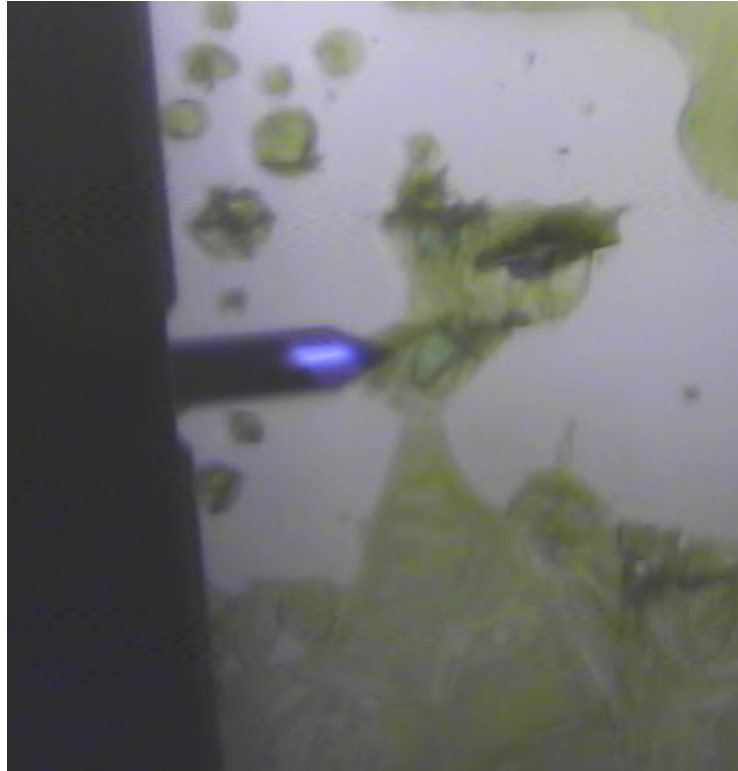
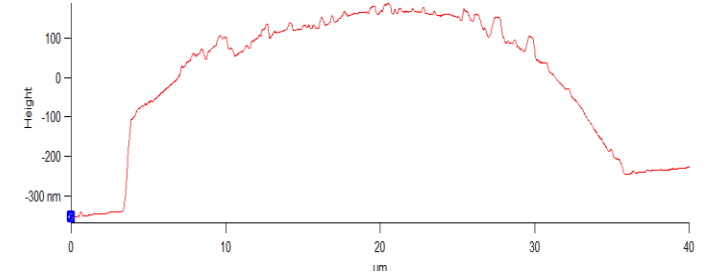
Optical survey



By using a light polarizer, we can exploit the linear dichroism of the sample grains to see the structure of the sample

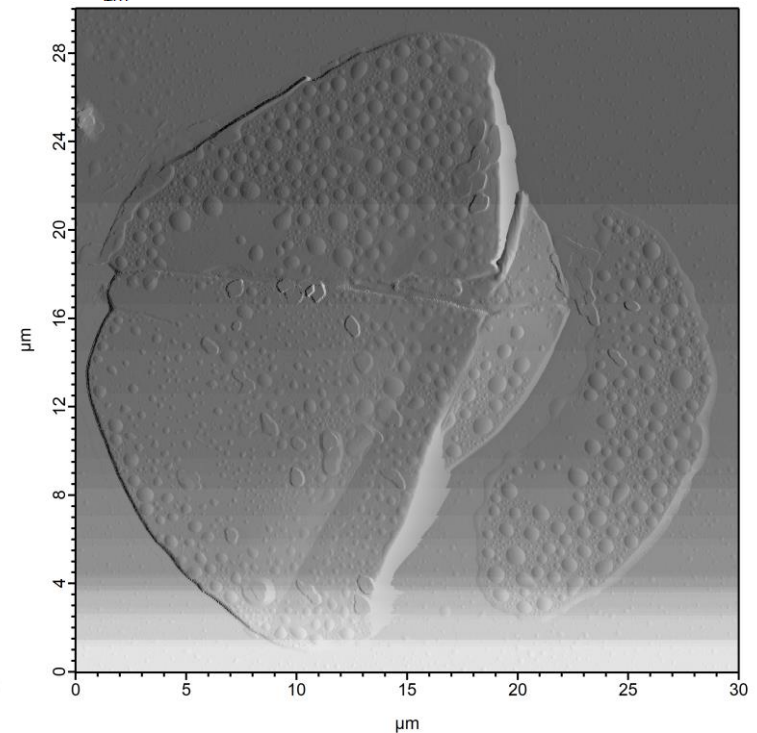
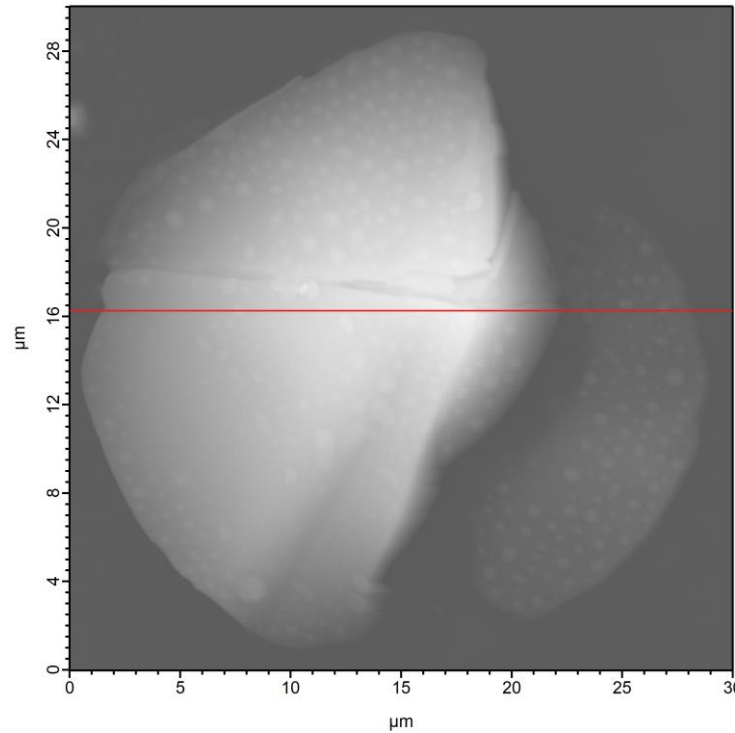
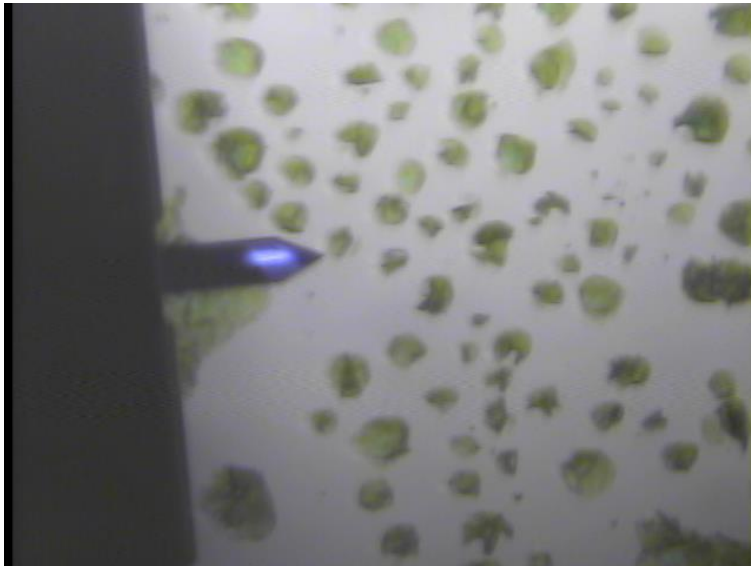
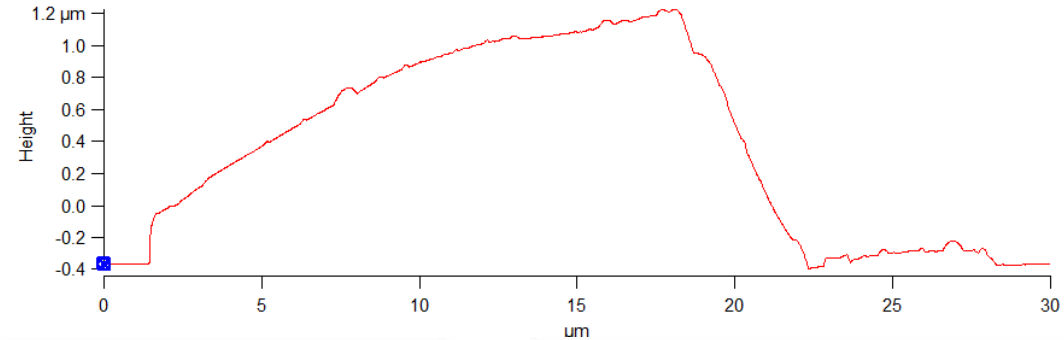


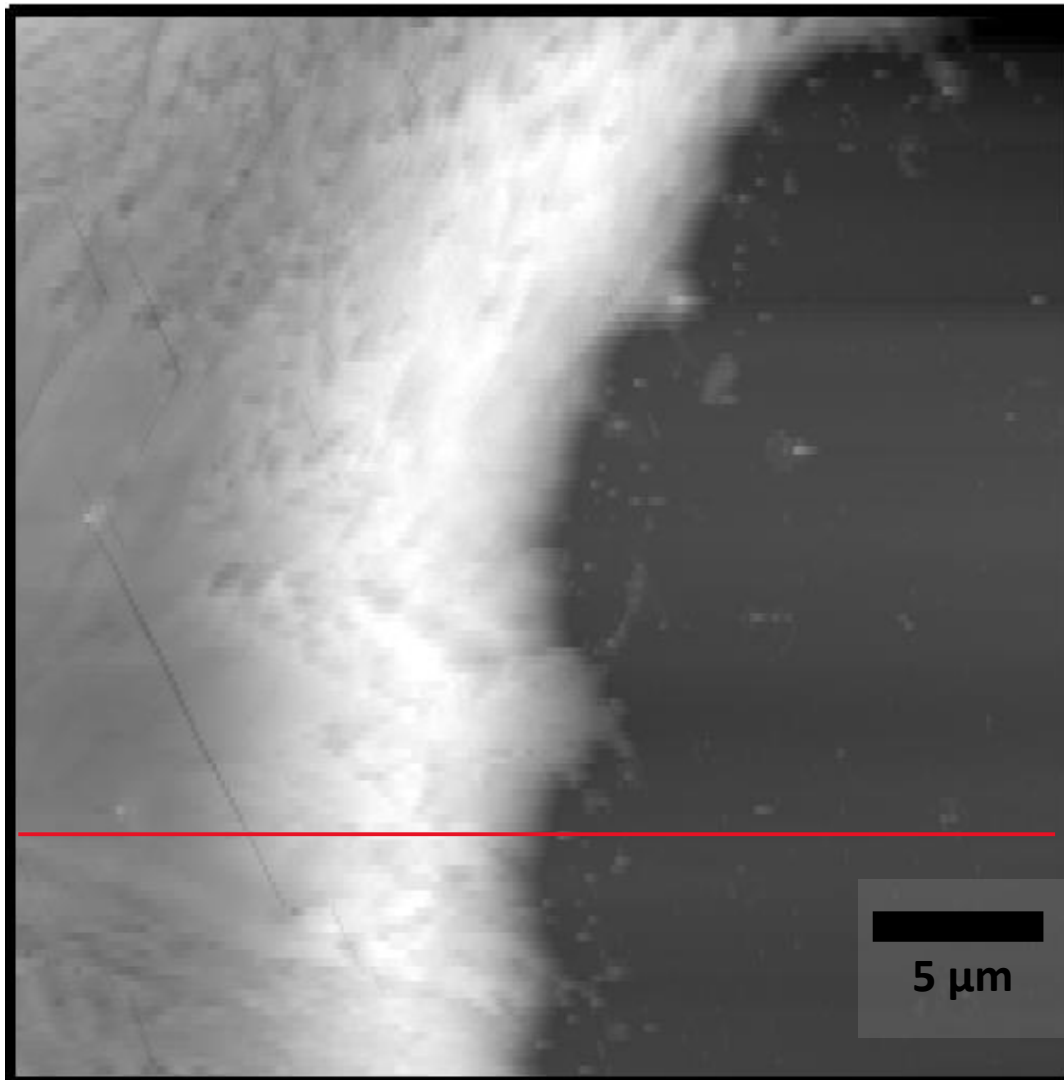
- Now that we have interesting places to scan, we'll bring our sample over to the AFM
- The AFM has an optical microscope inside to help us find the location of interest
- Then a navigation image is taken in order to precisely target the region of interest
- Once you've locked on the detailed imaging can start



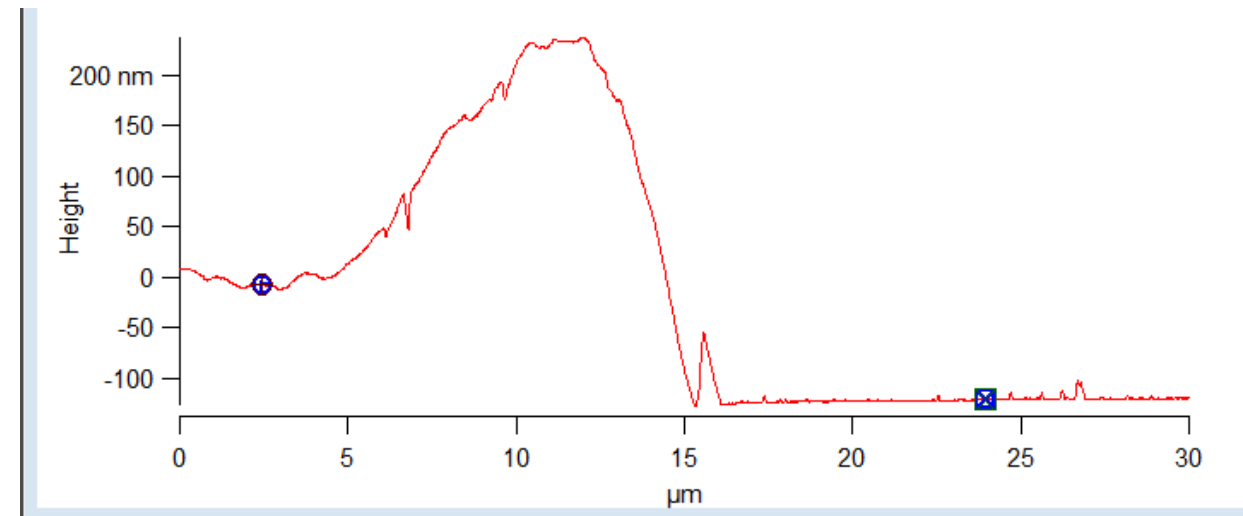
What can we learn from AFM image?

- An AFM image can reveal surface detail with nanometer resolution, much too small for even the best optical microscopes.

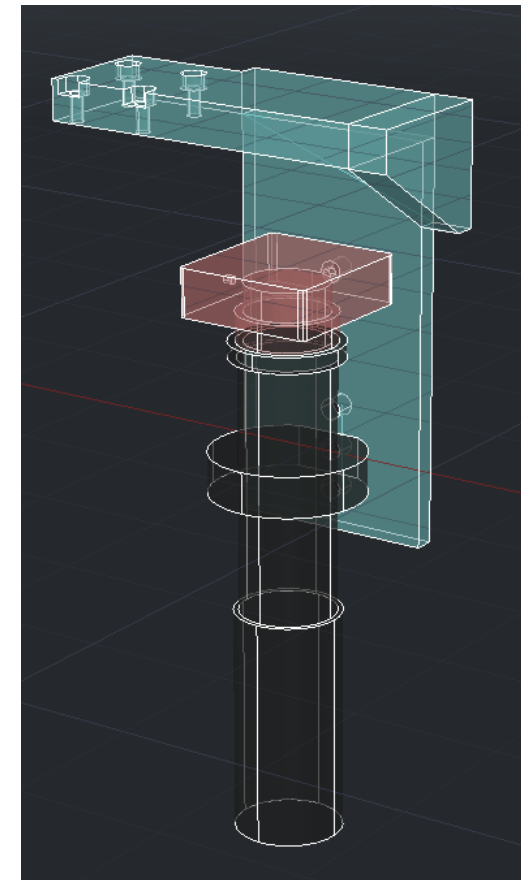
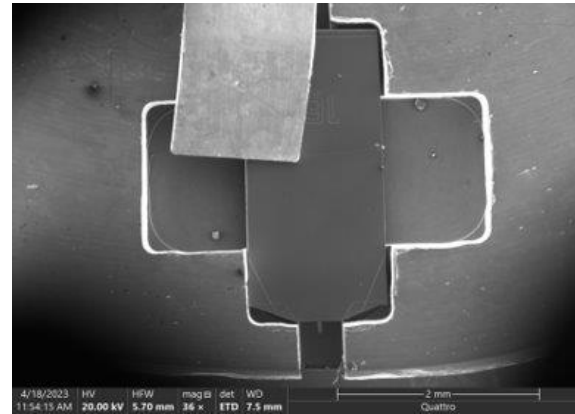
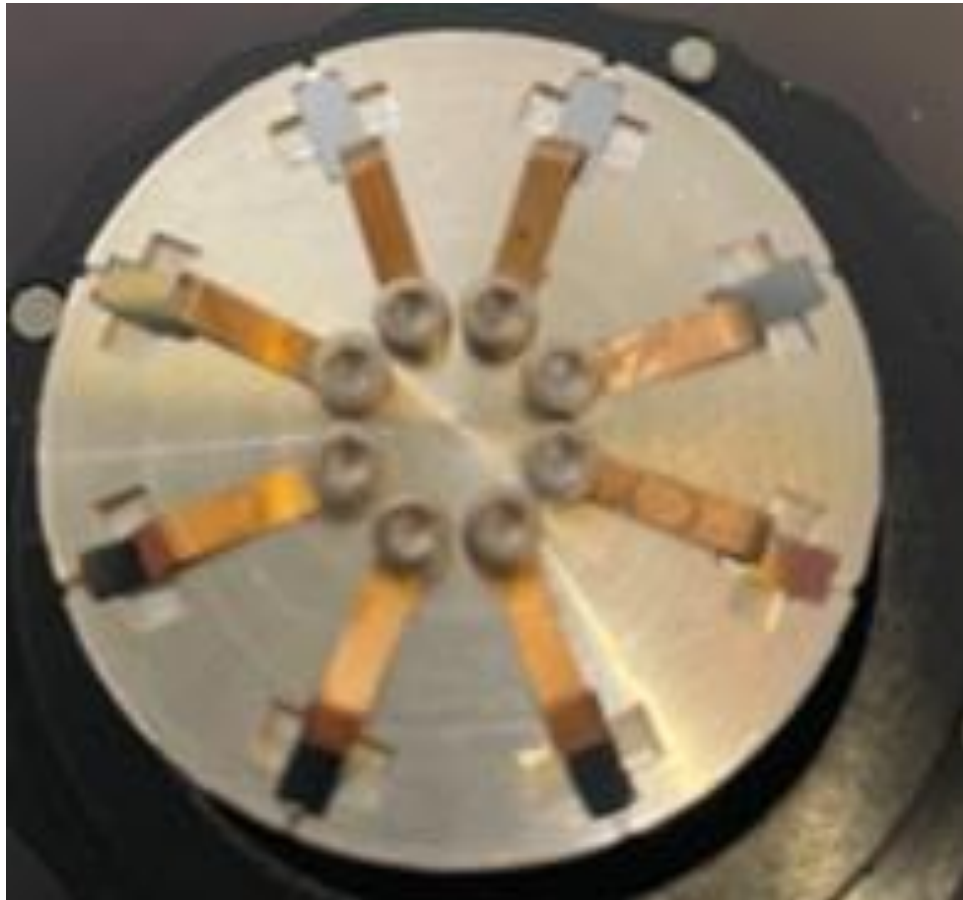




- AFM can also tell you how thick the sample is by imaging the edge and looking at the line scans from these images



- In addition to learning how to use the AFM, I also have designed some tools in AutoCAD for the AFM





Acknowledgements



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